

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	66	((wafer\$1 or semiconductor\$1 or chip\$1 or substrate\$1)with(repetit\$3 and non-repetit\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/10 09:08
L2	0	((wafer\$1 or semiconductor\$1 or chip\$1 or substrate\$1)with(repetit\$3 and non-repetit\$3))same patters	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/10 09:08
L3	0	((wafer\$1 or semiconductor\$1 or chip\$1 or substrate\$1)with(repetit\$3 and non-repetit\$3))same patten	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/10 09:08
L4	0	((wafer\$1 or semiconductor\$1 or chip\$1 or substrate\$1)with(repetit\$3 and non-repetit\$3))with patten	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/10 09:08
L5	11	1 and (cell or array or matrix)with(contrast or threshold)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/10 09:22
L6	11	1 and 5 and (detect\$3 or defects or fault or flaw)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/10 09:11
L7	4	6 and (cell or array or matrix)with(1D or one adj dimensional\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/10 09:23
L8	1	7 and @ad<"20011024"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/10 09:24